

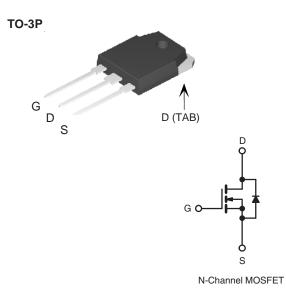
RoHS

COMPLIANT

## FPS40N60K-VB Datasheet

## N-Channel 600V(D-S) Super Junction Power MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V) at T <sub>J</sub> max.	600					
R <sub>DS(on)</sub> at 25 °C (Ω)	$V_{GS} = 10 V$	0.06				
Q <sub>g</sub> max. (nC)	273					
Q <sub>gs</sub> (nC)	46					
Q <sub>gd</sub> (nC)	79					
Configuration	Single					



## FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (C<sub>iss</sub>)
- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial
  - Welding
  - Induction heating
  - Motor drives
  - Battery chargers
  - Renewable energy
  - Solar (PV inverters)

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub>	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	600	V	
Gate-Source Voltage			V <sub>GS</sub>	± 30	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C	- I <sub>D</sub>	47		
		T <sub>C</sub> = 100 °C		30	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	142		
Linear Derating Factor				3.3	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	1410	mJ	
Maximum Power Dissipation			P <sub>D</sub>	415	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		-D (/-H	37		
Reverse Diode dV/dt <sup>d</sup>			dV/dt	9	V/ns	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	°C	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature.

- b.  $V_{DD}$  = 50 V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 10 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \leq I_D, \, dI/dt = 100$  A/µs, starting  $T_J = 25 \ ^\circ C.$



PARAMETER	SYMBOL	TYP.	MAX.		UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	- 40		°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-					
	L	•					
SPECIFICATIONS (T <sub>J</sub> = 25 °C, u	nless otherw	ise noted)					
PABAMETER	SYMBOL		T CONDITIONS	MIN.	TYP.	MAX.	UNI
Static				1			
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		600	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, $I_D = 1$ mA		-	0.70	-	V/°(
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>		$V_{DS} = V_{GS}, I_D = 250 \mu A$		-	4	V
	CO(III)	$V_{GS} = \pm 20 V$ $V_{GS} = \pm 30 V$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>			-	-	± 1	μA
Zero Gate Voltage Drain Current			= 650 V, V <sub>GS</sub> = 0 V	-	-	1	
	I <sub>DSS</sub>		∕, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	25	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	$I_D = 24 \text{ A}$	-	0.06	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 30 V, I <sub>D</sub> = 24 A	-	16.7	-	S
Dynamic		-		*	•	•	•
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ f = 1 MHz		-	5682	-	pF
Output Capacitance	C <sub>oss</sub>			-	251	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	1	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	$V_{DS} = 0$ V to 520 V, $V_{GS} = 0$ V		-	192	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	665	-	
Total Gate Charge	Qg	$V_{GS} = 10 \text{ V}$ $I_D = 24 \text{ A}, V_{DS} = 520 \text{ V}$		-	182	273	nC
Gate-Source Charge	Q <sub>gs</sub>			-	46	-	
Gate-Drain Charge	Q <sub>gd</sub>			-	79	-	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 520$ V, I <sub>D</sub> = 6 A, V <sub>GS</sub> = 10 V, R <sub>g</sub> = 9.1 Ω		-	47	94	ns
Rise Time	t <sub>r</sub>			-	87	131	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	156	234	
Fall Time	t <sub>f</sub>			-	103	206	
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.64	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	١ <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	47	A
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	139	
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 24 A, V <sub>GS</sub> = 0 V		-	0.9	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 24 \text{ A},$ dl/dt = 100 A/µs, V <sub>R</sub> = 25 V		-	753	1506	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	14	28	μΟ
Reverse Recovery Current	I <sub>RRM</sub>			-	28	-	A

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



## TYPCIAL CHARACTERISTICS (25 °C, unless otherwise noted)

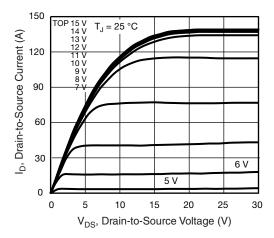


Fig. 1 - Typical Output Characteristics

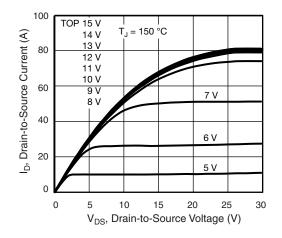


Fig. 2 - Typical Output Characteristics

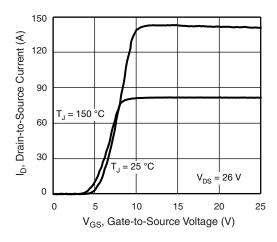


Fig. 3 - Typical Transfer Characteristics

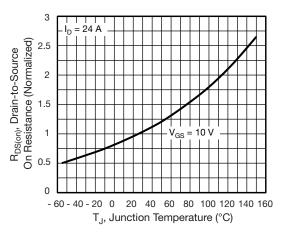


Fig. 4 - Normalized On-Resistance vs. Temperature

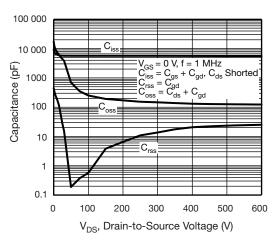


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

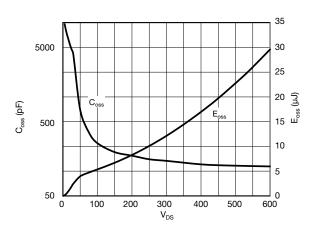


Fig. 6 - Coss and Eoss vs. VDS

## FPS40N60K-VB

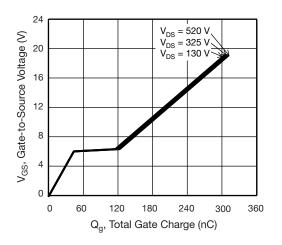


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

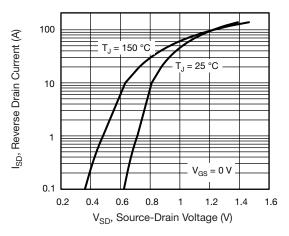


Fig. 8 - Typical Source-Drain Diode Forward Voltage

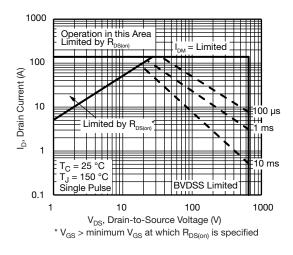
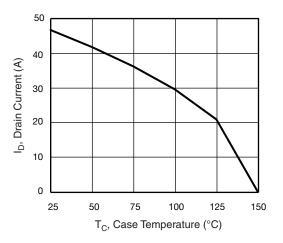


Fig. 9 - Maximum Safe Operating Area



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Fig. 10 - Maximum Drain Current vs. Case Temperature

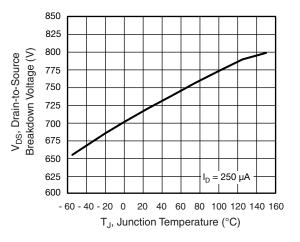
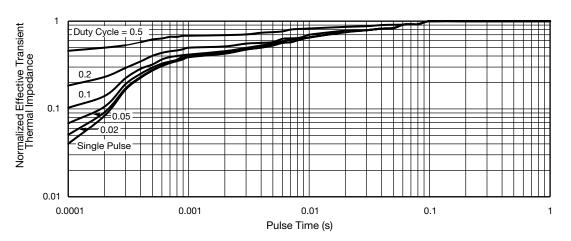


Fig. 11 - Temperature vs. Drain-to-Source Voltage





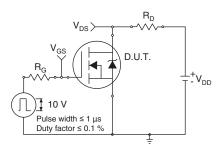


Fig. 13 - Switching Time Test Circuit

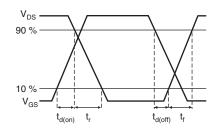


Fig. 14 - Switching Time Waveforms

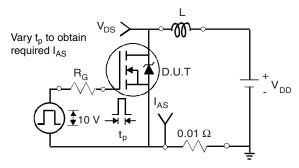


Fig. 15 - Unclamped Inductive Test Circuit

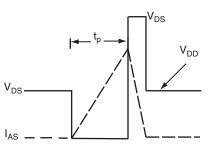


Fig. 16 - Unclamped Inductive Waveforms

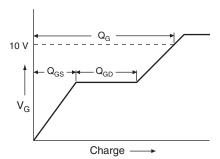


Fig. 17 - Basic Gate Charge Waveform

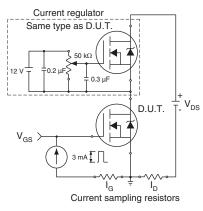


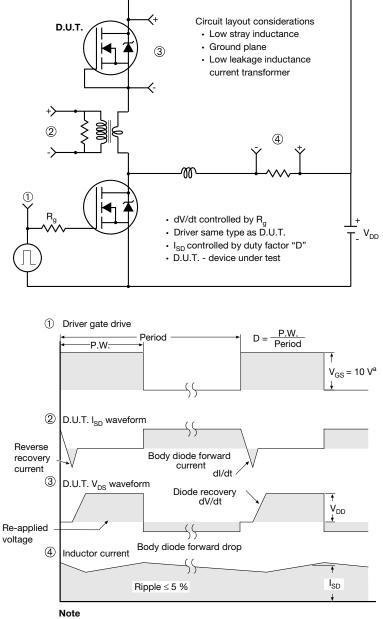
Fig. 18 - Gate Charge Test Circuit

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#### Peak Diode Recovery dV/dt Test Circuit



a.  $V_{GS} = 5 V$  for logic level devices

Fig. 19 - For N-Channel



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